

Search Notes

Application/Control No.

10/510,150

Examiner

Than Nguyen

Applicant(s)/Patent under
Reexamination

TAKASE ET AL.

Art Unit

2187

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
WEST Inventor IEEE	3/1/2007	NTV